Searcn Notes		
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Application/Control No.	Applicant(s)/Patent unde Reexamination	F
10/634,845	MURAYAMA ET AL.	
Examiner	Art Unit	
Jeffrey G. Hoekstra	3736	

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Class	Subclass	Date	Examiner
600	585	12/6/2005	JH
Updated	as above	5/22/2006	JH
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EAST Search	12/6/2005	JH
Updated as above	5/22/2006	JH